

Search Notes

Application/Control No.

10/724,717

Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under
Reexamination

SU, WEN-WEI

Art Unit

2636

SEARCHED

Class	Subclass	Date	Examiner
340	539.11	6/7/2005	JAT
	514	6/7/2005	JAT
	605	6/7/2005	JAT
	603	6/7/2005	JAT
702	188	6/7/2005	JAT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR